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# Effect of ZnO and PEDOT:PSS Charge Selective Layers on Photovoltage of Cuprous Oxide (Cu<sub>2</sub>O) Heterojunction Solar Cells

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#### **Abstract**

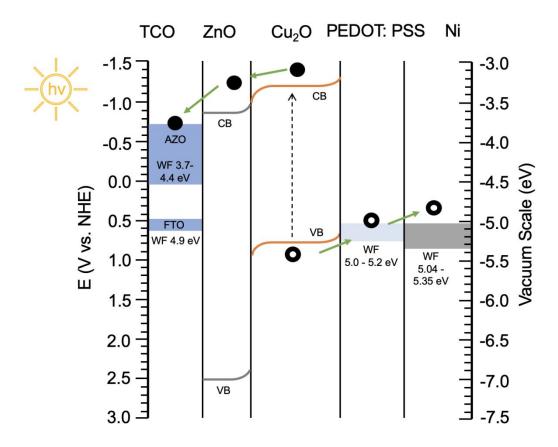
Electrochemical deposition (ECD) of Cu<sub>2</sub>O provides a scalable and low temperature pathway to solar cells with a theoretical high energy conversion efficiency of 23%, based on the 2.0-2.2 eV band gap of Cu<sub>2</sub>O. However, existing ECD-Cu<sub>2</sub>O devices are plagued by poor crystallinity and low selectivity of the electron and hole transport layers. Here we use Vibrating Kelvin Probe Surface Photovoltage Spectroscopy (VKP-SPV) to probe the charge transfer selectivity in FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS/Ni heterojunction solar cells. Selective electron extraction is achieved at the ZnO back contact to Cu<sub>2</sub>O, as confirmed by a negative surface photovoltage signal. While the uncoated Cu<sub>2</sub>O surface is electronselective due to the formation of a hole depletion layer, spin coating of a PEDOT:PSS film turns it into a hole-selective interface. After adding nickel metal ink top electrodes, functional 1.0 cm<sup>2</sup> solar cells with power conversion efficiency (PCE) of up to 0.07 %,195 mV open-circuit voltage, and 1.28 mA/cm<sup>2</sup> short-circuit photocurrent are achieved. The photovoltaic performance is higher for aluminum doped zinc oxide (AZO) substrates than for fluorine doped tin oxide (FTO) due to the presence of a n-/p-junction that further increases the electron selectivity of the AZO/ZnO/Cu<sub>2</sub>O contacts. Overall, this work demonstrates the first application of PEDOT:PSS as a hole transport layer (HTL) for Cu<sub>2</sub>O and the use of VKP-SPV to measure the photovoltage contributions of the Cu<sub>2</sub>O interfaces. The ability to fabricate Cu<sub>2</sub>O solar cells at near room temperature without the use of vacuum methods or rare elements is an important step towards a scalable Cu<sub>2</sub>O PV technology.

#### Introduction

Avoiding the most detrimental effects of climate change demands a rapid increase in the deployment rate of solar energy conversion devices. However, commercial photovoltaic cells utilize just a handful of semiconductors, incl. silicon, gallium arsenide, copper gallium indium sulfide, cadmium telluride, lead halide perovskite, and organic polymers, <sup>2</sup> which leaves considerable room for improvements. Emerging inorganic photovoltaic absorber materials such as binary and ternary chalcogenides 3, 4 offer comparable efficiencies and may be easier to produce on a large scale because no vacuum methods are required.<sup>5, 6</sup> The relatively high abundance of copper makes cuprous oxide (Cu<sub>2</sub>O) another promising photovoltaic absorber. 7-9 Based on its 2.0 - 2.2 eV bandgap, Cu<sub>2</sub>O cells can achieve up to 23% solar power conversion efficiency (PCE) 7, 9, 10 and photovoltaic quality Cu<sub>2</sub>O films can be grown by electrochemical deposition (ECD) from aqueous solutions. 11-14 In ECD, semiconductor films are formed by electrochemical reduction or oxidation of soluble precursors.<sup>8, 11, 13, 15-18</sup> This allows control over the growth rate via the current and the applied potential, and over doping levels by adjusting the electrolyte pH and metal ion concentration. 14, 19-22 Because the reaction involves electron transfer from the conductive substrate, conformal films can be grown over large areas, often at near room temperature. For example, British Petroleum used ECD for the manufacture of CdTe solar cell modules 0.94 m<sup>2</sup> in size (*Apollo process*). <sup>23</sup> Several groups also have reported Cu<sub>2</sub>O photovoltaics made by ECD. 11-14, 24 However, to date, the performance of ECD Cu<sub>2</sub>O cells does not vet reach that of thermally grown Cu<sub>2</sub>O (3.83-6%).<sup>12, 25, 26</sup> That is mainly due to the lower crystallinity and lower charge mobility (5 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) of ECD Cu<sub>2</sub>O compared to thermally grown Cu<sub>2</sub>O (100 cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>). <sup>7</sup> Also, the light penetration depth of Cu<sub>2</sub>O is quite large (>

 $2~\mu m$  at 600 nm) which necessitates relatively thick and highly crystalline films for complete light absorption and charge carrier extraction.<sup>7</sup> Finally, electrical contacts to  $Cu_2O$  often generate Cu(0), which limits the efficiency of junctions and causes photovoltage loss. <sup>27</sup>

To obtain further insight into these limitations, we use Vibrating Kelvin Probe-Surface Photovoltage Spectroscopy (VKP-SPV) as a tool to probe photochemical charge separation at ECD-grown Cu<sub>2</sub>O heterojunctions. This is done on Cu<sub>2</sub>O heterojunction photovoltaic cells that employ the superstrate device architecture shown in **Figure 1**. <sup>12</sup>. 13, 24 Here, ZnO serves as an electron transport layer (ETL) and Poly(3,4ethylenedioxythiophene): poly(4-styrene sulfonate) (PEDOT:PSS) is used as a HTL. ZnO is well suited as ETL for Cu<sub>2</sub>O because of its wide band gap of 3.37 eV and high electron mobility of ~120 cm<sup>2</sup>V<sup>-1</sup>s<sup>-1</sup>. PEDOT:PSS is widely applied as a HTL in organic photovoltaic devices <sup>28, 29</sup> and inorganic solar cells <sup>30-32</sup> because of its large work function (5.0 - 5.2 eV), p-type character, and high hole conductivity. <sup>33, 34</sup> However, this is the first example of using this HTL in combination with Cu<sub>2</sub>O. Functioning 1.0 cm<sup>2</sup> Cu<sub>2</sub>O solar cells are obtained after applying painted nickel ink as the top electrode. As we will show in the following, the performance of these devices is limited by pinholes in the Cu<sub>2</sub>O layers, high series resistance of the ZnO/Cu<sub>2</sub>O/PEDOT:PSS stack, and electron trapping at the Cu<sub>2</sub>O/PEDOT:PSS interface. Importantly, the charge selectivity of the Cu<sub>2</sub>O contacts can be observed with VKP-SPV, allowing a better understanding of the factors that control charge separation and energy conversion with Cu<sub>2</sub>O solar cells.



**Figure 1.** Energy diagram for FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS/Ni, showing values for work function (WF), band edges (CB and VB), and Fermi Levels (E<sub>f</sub>).

#### **Results and Discussion**

Cu<sub>2</sub>O photovoltaic devices were fabricated as shown in **Figure 2**. The first step consists of electrochemical deposition of the ZnO electron transport layer (ETL) onto a 1.00 cm<sup>2</sup> area of a commercial fluorine doped tin oxide (FTO) or aluminum doped zinc oxide (AZO) substrate, as previously described by Ghannam et al.  $^{35}$  This is achieved by applying a cathodic bias of -0.90 V vs SCE to a  $5.0 \times 10^{-3}$  M Zn(NO<sub>3</sub>)<sub>2</sub> electrolyte at 70 °C, resulting in reduction of nitrate to nitrite and the formation of hydroxide, as shown in **equation 1**.

The formed hydroxide then precipitates  $Zn(OH)_2$  on the working electrode (**equation 2**), which dehydrates to form crystalline ZnO (**equation 3**).

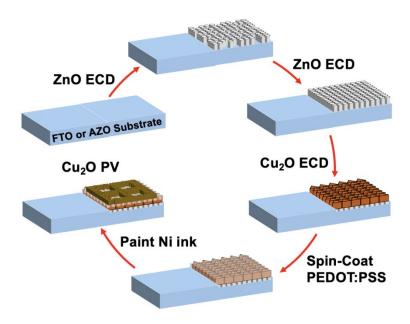


Figure 2. Device fabrication scheme.

$$NO_3$$
 +  $H_2O$  +  $2e$   $\rightarrow NO_2$  +  $2OH$  (Eq.1)

$$Zn^{2+} + 2 OH^{-} \rightarrow Zn(OH)_2$$
 (Eq.2)

$$Zn(OH)_2 \rightarrow ZnO + H_2O$$
 (Eq.3)

$$Cu^{2+} + e^{-} \rightarrow Cu^{+}$$
 (Eq.4)

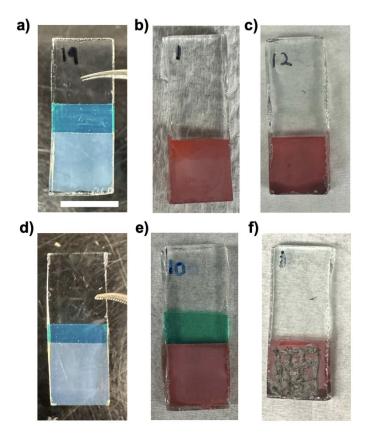
$$2 \text{ Cu}^+ + 2 \text{ OH}^- \rightarrow \text{Cu}_2\text{O} + \text{H}_2\text{O}$$
 (Eq.5)

To facilitate this dehydration reaction, the bath temperature was maintained at 70 °C. To reduce the concentration of residual pinholes, the electrodeposition process was repeated once more with the same pre-step voltage of -1.20 V and applied voltage of -0.90 V vs SCE. **Figure 3a** and **3d** show photos of the semi-transparent ZnO films on FTO

and AZO, respectively. ZnO films cover a 1x1 cm<sup>2</sup> area of the substrate and appear milky white due to light scattering.

As the next step, Cu<sub>2</sub>O is electrochemically deposited at -0.25 V to -0.40 V vs SCE from 0.40 M copper sulfate solution at 60 °C. This potential was chosen to maintain a steady current of approximately -0.80 mA. In the electrochemical synthesis of Cu<sub>2</sub>O, lactate (2hydroxypropanoic acid anion) is used as a complexing agent for the Cu(2+) ions. This prevents the precipitation of copper hydroxide (Cu(OH)<sub>2</sub>) under basic conditions of the experiment. Upon reaching the electrode surface, Cu<sup>2+</sup> ions undergo reduction to Cu<sup>+</sup> followed by deposition of Cu<sub>2</sub>O. The specific temperature of 60 °C was selected to promote the formation of Cu<sub>2</sub>O with larger grain sizes and to reduce electrical resistivity, as indicated in previous studies. <sup>36</sup> The pH of the solution was maintained at pH = 12 to ensure the p-type conductivity of the deposited Cu<sub>2</sub>O. It is well-documented that Cu<sub>2</sub>O synthesized under acidic conditions tends to exhibit n-type behavior. <sup>36</sup> Figures 3b and 3c show the characteristic purple-red color of Cu<sub>2</sub>O on ZnO on both FTO and AZO substrates, respectively. In the next fabrication step, a PEDOT:PSS layer was deposited by spin coating in air, followed by air-drying. Figure 3c shows the non-uniformity of the PEDOT: PSS film, seen as a dark region on the bottom of the photo. Due to its low contrast. PEDOT:PSS was not observable by scanning electron microscopy (SEM), but could be confirmed by energy dispersive X-ray spectroscopy (EDX). As seen in Figure S1, all elements (carbon, oxygen, and sulfur) could be detected. To finalize the device, a network of nickel (Ni) contacts was painted on the film using a fine brush. As illustrated in Figure 3f, these metal contacts exhibit a rough surface texture. The non-uniformity of these metal contacts presents potential sources of defects, while their increased thickness prevents

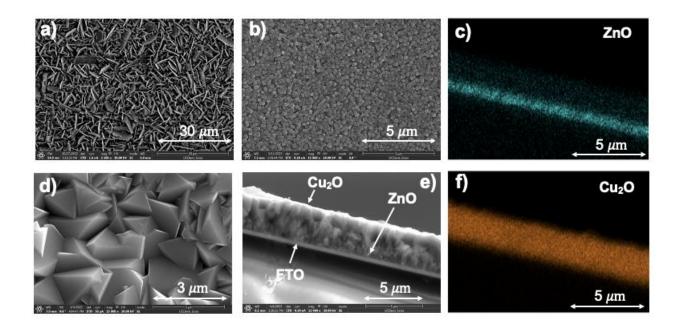
light from reaching the  $Cu_2O$  absorber. Therefore, these devices rely on illumination through the transparent FTO/AZO substrate. To observe the morphology and structure of the films, SEM images and X-ray diffraction (XRD) patterns were recorded. The ZnO nanorods are approximately 200 nm in diameter and 1 micrometer long, as shown in **Figures 4b and 4c**.



**Figure 3.** Photos of a) FTO/ZnO, b) FTO/ZnO/Cu<sub>2</sub>O, c) FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS and d) AZO/ZnO, e) AZO/ZnO/Cu<sub>2</sub>O, f) AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS/Ni. The blue and green regions are masking tape and the scale bar is 1.0 cm.

XRD patterns of the films (**Figure 5**) confirm the wurtzite structure of ZnO. Based on the enhanced (002) peak, the ZnO film in Figure **5b** has a preferential orientation of the c axis

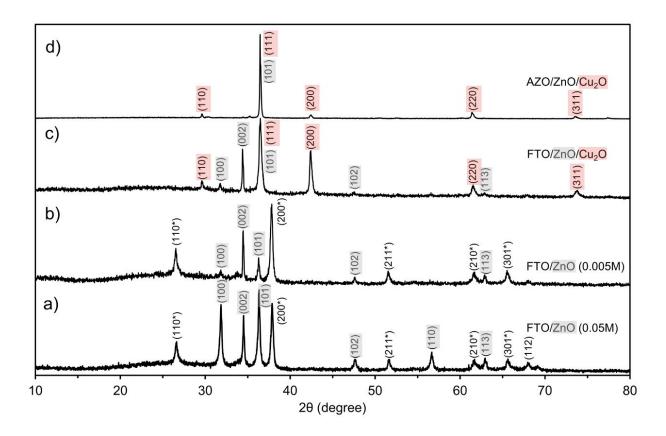
perpendicular to the FTO substrate. This agrees with the observed vertical orientation of the hexagonal nanorods in **Figure 4b**. Interestingly, ZnO nanoplates with a preferred (100) growth direction become accessible by increasing the  $Zn(NO_3)_2$  concentration in the electrolyte tenfold to  $0.05 \, \text{M} \, Zn(NO_3)_2$ . These plates can be identified in the SEM in **Figure 4a** and in the XRD in **Figure 5a**. According to Pradhan et al. <sup>37</sup> the (100) directional growth at high zinc nitrate concentrations is a result of the fast formation of  $Zn(OH)_2$  as an intermediate to ZnO.



**Figure 4.** SEM images for a) ZnO nanoplates deposited on FTO from 0.05 M Zn(NO<sub>3</sub>)<sub>2</sub> at -0.90 V vs SCE, b) ZnO nanorod array on FTO from  $5.0x10^{-3}$  M Zn(NO<sub>3</sub>)<sub>2</sub> at -0.90 V vs SCE, and d) Cu<sub>2</sub>O film on FTO/ZnO from 0.4 M CuSO<sub>4</sub> at -0.3 V vs SCE. Cross section SEM image of e) FTO/Cu<sub>2</sub>O/ZnO heterostructure, and EDX images for c) and f) ZnO and Cu<sub>2</sub>O, respectively.

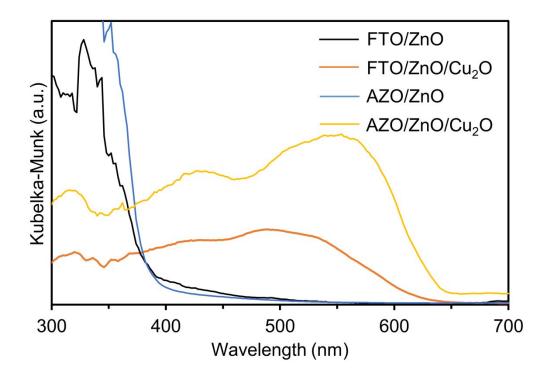
SEM images of the FTO/ZnO/Cu<sub>2</sub>O stacks are shown in **Figures 4d** and **e**. They confirm the presence of a uniform Cu<sub>2</sub>O film composed of truncated octahedral structures with an

average crystal size of about 5  $\mu$ m. This morphology is similar to that reported by Paracchino et al. <sup>36</sup> Powder XRD patterns in **Figure 5c** and **d** confirm the cuprite structure type, and reveal that on AZO/FTO, the Cu<sub>2</sub>O grains grow preferentially in the [111] direction, whereas no preferential orientation is seen on FTO/ZnO, based on the relative intensities of the (110), (111), and (200) peaks. <sup>38</sup> Based on cross section SEM images and elemental maps in **Figure 4c**, **4e**, and **4f**, the Cu<sub>2</sub>O layer is ~ 3  $\mu$ m thick and forms a well-defined phase boundary with ZnO.



**Figure 5.** X-ray diffraction patterns of ZnO grown on FTO from a)  $0.05 \, \text{M} \, \text{Zn}(\text{NO}_3)_2 \, \text{or b}) \, 5.0 \times 10^{-3} \, \text{M} \, \text{Zn}(\text{NO}_3)_2$  electrolyte. c) XRD patterns of FTO/ZnO/Cu<sub>2</sub>O, and d) of AZO/ZnO/Cu<sub>2</sub>O films. Miller indices marked \* are from FTO. Peak assignments for Cu<sub>2</sub>O and ZnO are from Ho et al. <sup>38</sup> and Pradhan et al, <sup>37</sup> respectively. The disappearance of the ZnO diffraction peaks in d) is due to shading of the X-rays by the thick Cu<sub>2</sub>O overlayer.

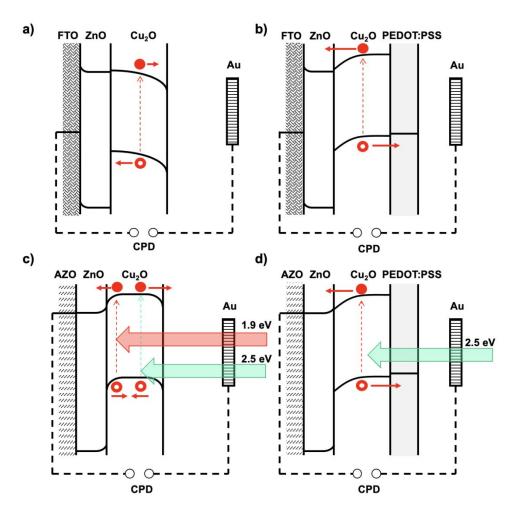
Diffuse reflectance spectra for the stacks are summarized in **Figure 6**. The ZnO films on AZO and FTO have absorption onsets at 380 nm (3.26 eV) or 390 nm (3.18 eV), characteristic of the known band gap of ZnO (3.37 eV). <sup>13</sup> The ZnO/Cu<sub>2</sub>O bilayers for both AZO and FTO substrates show the absorption edge at 625-640 nm (1.98 - 1.94 eV), slightly below the known band gap of Cu<sub>2</sub>O (2.0 - 2.2 eV). <sup>7</sup> The absorption of ZnO is no longer observed because of shading from the Cu<sub>2</sub>O layer. Spectra for the PEDOT:PSS coated stacks (**Figure S2**) are similar to the FTO/ZnO/Cu<sub>2</sub>O and AZO/ZnO/Cu<sub>2</sub>O samples, except for a small shift of the absorption onset to 640-655 nm (1.94 -1.89 eV). This is a result of the smaller bandgap of PEDOT:PSS (1.76 eV). <sup>39</sup>



**Figure 6**. Diffuse reflectance optical spectra for FTO/ZnO, FTO/ZnO/Cu<sub>2</sub>O, AZO/ZnO, and AZO/ZnO/Cu<sub>2</sub>O. The weak visible absorption of the AZO/ZnO and FTO/ZnO samples is an artefact of

the diffuse reflectance measurement. It is attributed to transmission losses resulting from the thin ZnO film.

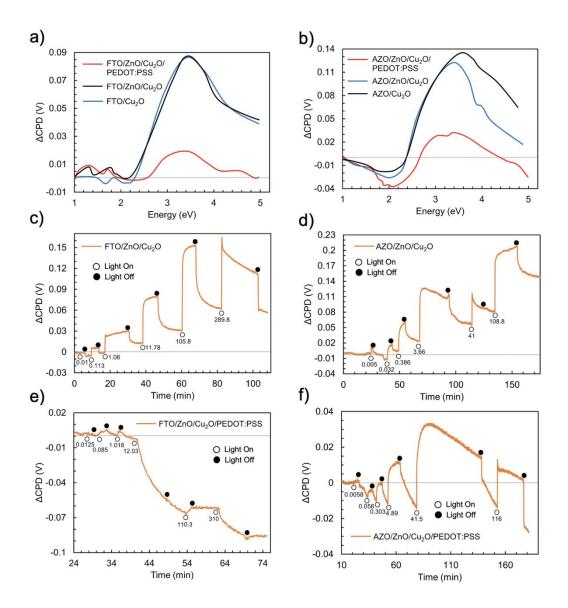
To probe the ability of the films to generate a photovoltage, Vibrating Kelvin Probe Surface Photovoltage spectroscopy (VKP-SPS) was applied. In VKP-SPV, the surface photovoltage signal—the change in the contact potential difference (CPD)—under illumination (SPV = CPD(light) - CPD(dark)) is measured with a vibrating Kelvin probe, as shown in **Figure 7a**. The SPV signal provides the direction of carrier separation and the effective bandgap of semiconductors.  $^{40-42}$  For sufficiently conductive samples that are in electrochemical equilibrium in the dark (constant  $E_F$ ), the SPV signal equals the photovoltage, i.e. the open circuit potential of the corresponding solar cell.  $^{43-46}$  SPV spectra for ZnO/CuO<sub>2</sub> films on FTO and AZO are shown in **Figure 8a and 8b**.



**Figure 7.** Charge separation scheme for a) FTO/ZnO/Cu<sub>2</sub>O, b) FTO/ZnO/Cu<sub>2</sub>O/ PEDOT:PSS, c) AZO/ZnO/Cu<sub>2</sub>O, and d) AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS.

The major photovoltage onset occurs near 2.2 eV, slightly above the optical band gap value of Cu<sub>2</sub>O (2.0 eV). This confirms that the SPV signal is due to excitation of Cu<sub>2</sub>O, but also shows that photochemical charge separation in Cu<sub>2</sub>O is not efficient in the 2.0-2.2 eV photon energy range. Both FTO and AZO substrates yield positive photovoltage, indicating that electrons (minority carriers) are moving towards the Kelvin probe, as shown in **Figure 7a**. This indicates that charge carrier separation is controlled by the hole depletion layer at the Cu<sub>2</sub>O surface. However, the positive signal decreases significantly after adding the hole transfer layer PEDOT:PSS to the Cu<sub>2</sub>O surface. This suggests a

reduction in band bending at the Cu<sub>2</sub>O/PEDOT:PSS interface. Indeed, because of its high work function (5.0 - 5.2 eV) <sup>33, 34</sup> PEDOT:PSS is expected to form an ohmic contact with Cu<sub>2</sub>O (Figure 7b). SPV spectra for Cu<sub>2</sub>O films deposited on AZO substrates are similar (Figure 8b), except that the main positive SPV signal is preceded by negative SPV signals at 1.2-2.2 eV. A similar SPV inversion has been previously observed for junctions formed at n-Si/p-GaN and Au/n-SrTiO<sub>3</sub> interfaces. 47, 48 The signal is due to charge carriers moving in the Cu<sub>2</sub>O depletion region at the n-ZnO/p-Cu<sub>2</sub>O contact, as shown in the energy diagram in Figure 7c. Because light with energy below 2.0 eV can penetrate the Cu<sub>2</sub>O layer, it can excite interfacial states near the Cu<sub>2</sub>O back contact and probe the band bending there. The n-ZnO/p-Cu<sub>2</sub>O junction is a result of the reducing workfunction of AZO ( $\sim 3.7 - 4.4 \text{ eV}$ ), <sup>49</sup> which moves the ZnO Fermi level to more reducing potentials. This is not seen for the FTO/ZnO/Cu<sub>2</sub>O contact because the FTO workfunction (4.9 eV) is more oxidizing than AZO. 50 The spectra in Figure 8b also reveal that the negative photovoltage (and the band bending at the n-ZnO/p-Cu<sub>2</sub>O contact) increases in order AZO/Cu<sub>2</sub>O < AZO/ZnO/Cu<sub>2</sub>O < AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS. This reflects the increasing workfunction difference between the back and front of these multilayer configurations. The electron selectivity of the ZnO/Cu<sub>2</sub>O contact is key to the operation of the solar cell in Figure 1. The SPV results show that this electron selectivity it is not only enabled by the deep valence band of the ZnO layer, which rejects photoholes (Figure 1), but also by the n-/p-junction at the ZnO/Cu<sub>2</sub>O interface, which creates an electrostatic barrier for hole transfer.



**Figure 8.** a) SPV spectra for FTO/Cu<sub>2</sub>O, FTO/ZnO/Cu<sub>2</sub>O, FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS and for b) AZO/Cu<sub>2</sub>O, AZO/ZnO/Cu<sub>2</sub>O, AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS. SPV under intermittent illumination for c) FTO/ZnO/Cu<sub>2</sub>O, d) AZO/ZnO/Cu<sub>2</sub>O, e) FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS, f) AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS. Numerical values indicate the irradiance (mW/cm<sup>2</sup>) of the LED light (400 nm) at the sample.

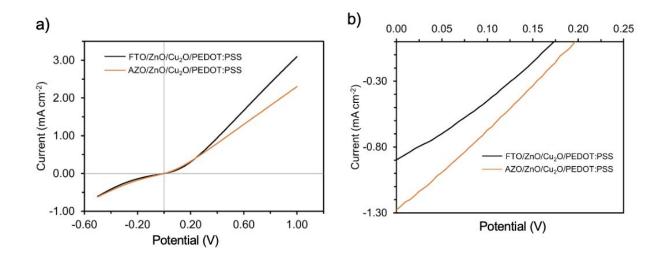
Lastly, the rough (large) interface between the ZnO and  $Cu_2O$  layers (**Figure 4b**) favors the transfer of minority carriers, whose shorter lifetime reduces their diffusion length, compared to the longer-lived majority carriers (holes). <sup>51, 52</sup> Conversely, the positive SPV signal at > 2.4 eV is mainly due to excitation of the  $Cu_2O$  front contact, as shown in **Figure** 

**7c.** This signal decreases considerably with the addition of PEDOT:PSS, as seen before for the FTO deposited films. This confirms that PEDOT:PSS promotes hole collection from Cu<sub>2</sub>O. Without PEDOT:PSS, charge separation at the Cu<sub>2</sub>O front would be controlled by a p-type depletion layer, as shown in **Figure 7a and 7c**, resulting in a dysfunctional device.

To better observe charge separation near the Cu<sub>2</sub>O/PEDOT:PSS contact, SPV experiments were repeated with higher light intensities at a fixed wavelength of 400 nm (3.1 eV). This light predominantly probes the top Cu<sub>2</sub>O contact, due to the short optical penetration depth ( $1/\alpha = 40$  nm) of Cu<sub>2</sub>O at this wavelength ( $\alpha = 2.5 \times 10^5$  cm<sup>-1</sup> at 400 nm). 53 SPV signals in Figures 8c - f increase with light intensity, but show low reversibility, based on the residual SPV signal after turning off the light. For example, 90% of the SPV signal in Figure 8e remains after illuminating the FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS stack with 12.03 mW cm<sup>-2</sup> light. That shows that charge carriers get trapped at the Cu<sub>2</sub>O interfaces, likely in defects arising from dangling bonds and surface states.<sup>54, 55</sup> Again, both FTO/ZnO/Cu<sub>2</sub>O and AZO/ZnO/Cu<sub>2</sub>O structures show positive photovoltage that agrees with the charge separation schemes in Figure 7a and 7c. The native Cu<sub>2</sub>O surface is electron selective, due to the formation of a p-type depletion layer. However, after addition of the PEDOT:PSS films (Figure 8ef), positive photovoltage values are diminished in size or even inverted. For example, the AZO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS stack in Figure 8f gives a diminished positive photovoltage of only 0.05 mV at 116 mW cm<sup>-2</sup>, compared to 220 mV at 108.8 mW cm<sup>-2</sup> for the AZO/ZnO/Cu<sub>2</sub>O stack. And for FTO/ZnO/Cu<sub>2</sub>O/PEDOT:PSS, the SPV under 12.03 mW cm<sup>-2</sup> in Figure 8e is now negative (- 70 mV). While the differences between the data in Figures 8e and f are

attributed to variations in PEDOT:PSS coverage, and are not diagnostic, the comparison with **Figures 8cd** prove that the polymer removes the Cu<sub>2</sub>O band bending at the surface and turns it into a flat band. This is shown in the energy diagrams in **Figure 7b and 7d.** Accordingly, electron-hole separation in Cu<sub>2</sub>O does not take place at the Cu<sub>2</sub>O interface with PEDOT:PSS, as demonstrated by the absence of a strong negative SPV signal, but at the interface to the ZnO ETL.

Finally, **Figure 9** shows representative current-voltage (I-V) curves for the completed FTO- and AZO-grown devices. In the dark, devices exhibit rectifying behavior based on the shape of the I-V plot. In both cases, the rectification stems from the ZnO/Cu<sub>2</sub>O heterojunction (**Figure 1**). To assess the photovoltaic effect, devices were illuminated with simulated sunlight from a Xe arc lamp (100 mW cm<sup>-2</sup>) through the transparent FTO or AZO substrate (Data in **Tables 1** and **S3-4**).



**Figure 9.** Current density versus applied potential (versus FTO/AZO counter electrode) in the dark (a) and (b) under simulated AM 1.5 illumination.

I-V curves in **Figure 9b** exhibit the expected shift to negative current. The FTO device reveals a short circuit current density ( $J_{SC}$ ) of 0.90 mA/cm<sup>2</sup>, an open circuit voltage ( $V_{OC}$ )

of 160 mV, and a fill factor of 27.1%. Cells on the AZO substrate yield almost 1.5 times the  $J_{SC}$  (1.28 mA/cm²), a higher  $V_{OC}$  (195 mV), and a higher power conversion efficiency (PCE; 0.07%). The improved performance can be attributed to the n-ZnO/p-Cu<sub>2</sub>O junction as mentioned in the discussion of the SPV data. This junction exists only in the AZO based devices and aids the electron selectivity of the ZnO/Cu<sub>2</sub>O contact. However, the hole selective PEDOT:PSS contact is also required. Without it, the FTO/ZnO/Cu<sub>2</sub>O/Ni device only gives a very small photocurrent of 1  $\mu$ A (**Table 1**). No net charge separation is achieved because of the opposing polarity of the junctions at the two Cu<sub>2</sub>O interfaces (energy diagram in **Figure 7c**).

**Table 1.** Photovoltaic properties of Cu<sub>2</sub>O solar cells under AM 1.5 illumination.

Sample	Jsc (mA/cm²)	Voc (V)	FF (%)	PCE
FTO/ZnO/Cu <sub>2</sub> O/Ni	0.001 ± 0.001	0.20 ± 5.68	-	-
FTO/ZnO/Cu <sub>2</sub> O/PE	0.90 ± 0.09	0.16 ± 3.19	27.06 ± 2.56	0.039 ± 0.004%
DOT:PSS/Ni				
AZO/ZnO/Cu <sub>2</sub> O/PE	1.28 ± 0.14	0.20 ± 7.40	27.24 ± 0.90	0.068 ± 0.01%
DOT:PSS/Ni				

The I-V data also reveals low fill factors and PCE for all devices. This is attributed to the presence of pinholes in the 1.00 cm<sup>2</sup> devices, as evidenced by the positive slope in the reverse bias direction. The inverse relationship between solar energy conversion performance and area size is well established in the field.<sup>3,56</sup> The low photocurrent of the devices can be attributed to a high series resistance, which follows from the low slope of the I-V curve under forward bias. Lastly, electron trapping at the Cu<sub>2</sub>O/PEDOT:PSS interface is an issue, as seen in the SPV data in **Figure 8f**. The problem may be overcome

with other HTLs. Lastly, the data in **Figure S5** shows that photocurrents and open circuit voltages form reversibly and remain stable over the course of a few minutes. This demonstrates the absence of significant photocorrosion during operation of the devices in air.

#### Conclusion

Overall, we demonstrate the first FTO(AZO)/ZnO/Cu<sub>2</sub>O/PEDOT:PSS/Ni heterojunction solar cells with a device area of 1.0 cm<sup>2</sup>. Devices are fabricated in superstrate configuration by sequential electrodeposition of ZnO and Cu<sub>2</sub>O films from aqueous electrolytes, followed by spin-coating of PEDOT:PSS and application of nickel ink. Under AM 1.5 illumination, devices achieve up to 0.07% power conversion efficiency, 195 mV  $V_{\rm OC}$ , and 1.28 mA/cm<sup>2</sup>  $J_{\rm SC}$ . The low performance can be attributed to pinholes in the Cu<sub>2</sub>O layers, high series resistance, and non-optimal band offsets at the ZnO/Cu<sub>2</sub>O and Cu<sub>2</sub>O/PEDOT:PSS interfaces. For the first time, Vibrating Kelvin Probe-SPV is used to probe the effect of the charge-selective layers on charge separation. This reveals that selective electron extraction by the ZnO ETL is not just a result of the deep ZnO valence band, which rejects Cu<sub>2</sub>O photoholes, but also caused by a n-/p-junction which adds an electrostatic barrier for hole transfer. This barrier is observed as an inverted SPV signal under Cu<sub>2</sub>O sub-band gap illumination. The barrier is only present in the AZO deposited films, due to the more reducing workfunction of this material compared to FTO. It explains the better performance of the AZO over the FTO devices. While the bare Cu<sub>2</sub>O surface is electron-selective due to the presence of a hole depletion layer, the addition of PEDOT:PSS creates a hole-selective contact with Cu<sub>2</sub>O. However, electron trapping at the Cu<sub>2</sub>O/PEDOT:PSS interface is still prevalent and contributes to a low open circuit potential of the completed devices. Solving this problem is a topic of ongoing studies in the lab. Overall, we have described a simple and scalable pathway to Cu<sub>2</sub>O photovoltaic cells and diagnostic tools to observe the junctions that drive charge separation in them.

#### **Experimental Section**

Zinc nitrate hexahydrate (99% metal basis, Alfa Aesar), cupric sulfate pentahydrate (Fine crystals, EM Science), sodium phosphate dibasic heptahydrate (Na<sub>2</sub>HPO<sub>4</sub>·7H<sub>2</sub>O,  $\geq$  98.0% Sigma-Aldrich), sodium hydroxide (NaOH,  $\geq$  97.0% Sigma-Aldrich), ethyl alcohol (CH<sub>3</sub>CH<sub>2</sub>OH, PG II Koptec), acetone ((CH<sub>3</sub>CH<sub>3</sub>CO,  $\geq$  99.0% Sigma-Aldrich), lactic acid (CH<sub>3</sub>CHCOOH, Sigma Life Science), poly(3,4-ethylenedioxythiophene)-poly(styrenesulfonate) (PEDOT:PSS, Aldrich), DMSO (BDH, 99.9%), zinc wire (99.95% metal basis, Alfa Aesar), aluminum-doped zinc oxide (AZO, MSE), fluorine-doped tin oxide (FTO, MSI) and Triton X-100 (USB Corporation) were purchased from the respective vendors and used without further purification. Water was purified to 18 MΩ·cm resistivity using a Nanopure system.

**Growth of ZnO.** Electrochemical deposition of ZnO was performed in a crystallization round dish on a hotplate, using a procedure adapted from Wei et al.  $^{13}$  and Ghannam et al.  $^{35}$  The bath was open to air and stirred constantly at 100 rpm and heated to 70 °C. The three-electrode configuration used either 1.0 cm² aluminum doped zinc oxide (AZO) or fluorine doped tin oxide (FTO) as working electrodes, a 3.5 M KCl calomel reference electrode, and a Zn rod as counter electrode. Before deposition, AZO and FTO were cleaned with soap, water, ethanol, and acetone by sonication for 15 minutes in each solvent. During deposition, AZO and FTO electrodes were contacted with a Ni/Fe alligator clip. The aqueous  $5.0 \times 10^{-3}$  M  $Zn(NO_3)_2 \cdot 6$  H<sub>2</sub>O electrolyte was prepared by dissolving 0.0372 g of  $Zn(NO_3)_2 \cdot 6$  H<sub>2</sub>O in 25 mL H<sub>2</sub>O. The low concentration is essential to achieving a nanorod morphology. ZnO growth was carried out in chronoamperometry mode using

a pre-step voltage of -1.2 V vs SCE for 15 s followed by a deposition voltage of -0.90 V vs SCE for 5 mins. Under these conditions, ZnO deposits as shown in **equations 1-3**. During deposition, the current was maintained at -0.35 mA cm<sup>-2</sup>. During this time, the Zn counter electrode turns grey due to oxidation. Additionally, observable bubbles emerge on the surface of the working electrode, indicative of H<sub>2</sub> gas generation. After deposition, the electrode was removed, rinsed with water, and dried in air. Typically, one 25 mL electrolyte bath can be used to fabricate one to three 1.0 cm<sup>2</sup> ZnO films.

**Growth of Cu<sub>2</sub>O film.** Cu<sub>2</sub>O was electrodeposited with the same cell as above, using the 1.0 cm<sup>2</sup> FTO/ZnO electrode, a Pt wire counter electrode, and a 3.5 M KCl calomel reference electrode. The procedure was adapted from Wei et al.<sup>13</sup> The electrolyte consisted of a lactate-stabilized copper sulfate solution, which was made by dissolving 4.99 g of CuSO<sub>4</sub>·5H<sub>2</sub>O, 13.40 g of Na<sub>2</sub>HPO<sub>4</sub>·7H<sub>2</sub>O, and 26.297 mL of 3 M Lactic Acid in DI water to a final solution volume of 100 mL. The pH of the electrolyte was adjusted to pH 12 by titrating in 2.0 M NaOH. Electrodeposition was carried out using chronoamperometry at a constant voltage of -0.3 V vs SCE and constant stirring of the electrolyte at 100 rpm. The temperature was fixed at 60 °C and the deposition time was 35 minutes. The chemistry of Cu<sub>2</sub>O electrodeposition is given in **equations 4** and **5**. During deposition, the current varied from -0.8 mA cm<sup>-2</sup> to -1.6 mA cm<sup>-2</sup>. After deposition, the electrode was removed and rinsed, and dried in air. Typically, one 25 mL electrolyte bath can be used to fabricate two 1.0 cm<sup>2</sup> Cu<sub>2</sub>O films. Cu<sub>2</sub>O films were stored in air in the dark until further processing.

**Spin Coating of PEDOT:PSS.** A PEDOT:PSS film was deposited by spin-coating using a mixture of 2.5 mL PEDOT:PSS solution (3.2% w/v in water), 0.5 mL DMSO, 0.1 mL

Triton X-100 and enough water to produce a total volume of 10 mL. The solution was stored in a refrigerator (5°C) before use. Spin-coating used a rate of 700 rpm for 4 minutes. Afterwards, the film was dried at 70 °C for 35 minutes on a hot plate.

Nickel metal contacts were applied using nickel conductive paint (*MG Chemicals*, 841AR Super Shield). A fine brush was used to paint a network of metal contacts, which were then dried with a heat gun at approximately 70 °C for 5 minutes. Devices were stored in air for 24 hours before measurements.

#### Characterization

Scanning electron micrographs (SEM) were collected on a FEI Scios Dual Beam FIB/SEM microscope with Oxford X-Max Energy Dispersive X-ray Spectroscopy (EDX) detector and an accelerating voltage of 10-30 kV. UV-Vis diffuse reflectance spectra were recorded using a Thermo Scientific Evolution 220 Spectrophotometer. Powder X-ray diffraction data were collected using a D8 Eco Advance Powder X-ray diffractometer with Lynx-EX detector. Surface photovoltage (SPV) measurements were conducted under vacuum (≤ 1.2 x 10-4 mbar pressure) using a vibrating gold Kelvin probe (*Delta PHI Besocke*). Samples were illuminated using a 300 W Xe lamp filtered through an *Oriel Cornerstone* 130 monochromator. SPV signals plotted in the figures equal the change of the contact potential difference (CPD) between light and dark conditions: SPV(V) = CPD(light)- CPD(dark).

Current-voltage (I-V) measurements for solar cells were performed using a *Gamry Instruments Interface 1010E* potentiostat connected to a PC. The lead for the working electrode was attached to the Ni metal contact while the leads for the counter and

reference electrode were combined and attached to the conductive substrates. For measurements under illumination, a 300 W Xe lamp was used as the light source and the beam was focused onto the solar cell using a mirror. The light intensity was calibrated to 1 sun (AM 1.5G) illumination using the current output from a commercial silicon solar cell. I-V Scans were performed from -0.5 V to 1.0 V at a 30 mV/s scan rate.

#### **Conflicts of interest**

The authors declare that they have no competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

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#### **Supporting information**

Energy dispersive X-ray and photovoltaic device data.

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